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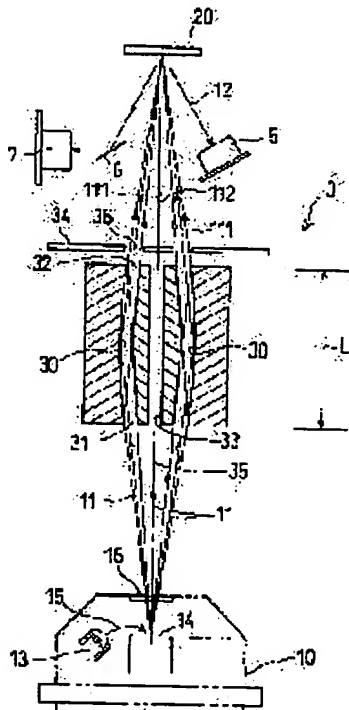
(21)Application number : 11-310911

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(54) X-RAY SPECTROMETER AND X-RAY DIFFRACTOMETER



(57)Abstract:

PROBLEM TO BE SOLVED: To provide an X-ray spectrometer and an X-ray diffractometer which fit to analyze light elements, and heavy elements of a minute amount without losing a compactness as a portable type.

SOLUTION: The X-ray spectrometer has a looped spectroscopic element 30 for splitting X rays by an inner circumferential face. A total reflecting collimator 3 for totally reflecting and collecting X rays by an inner surface is set on a nearly equal axis of the spectroscopic element 30 inside the spectroscopic element 30.

LEGAL STATUS

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